NDA-320-D

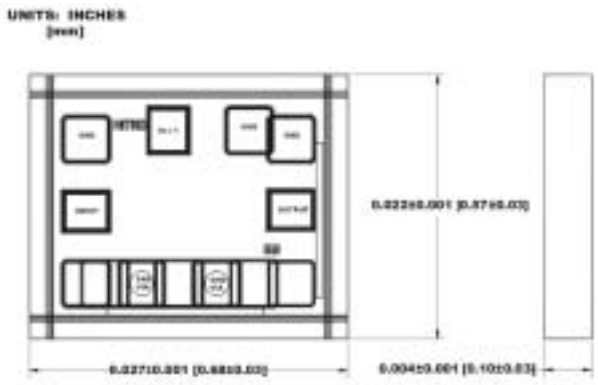
GaInP/GaAs HBT MMIC DISTRIBUTED AMPLIFIER DC TO 12GHz

Typical Applications

- Narrow and Broadband Commercial and Military Radio Designs
- Linear and Saturated Amplifiers
- Gain Stage or Driver Amplifiers for MW Radio/Optical Designs

Product Description

The NDA-320-D Casacadable Broadband GaInP/GaAs MMIC amplifier is a low-cost, high-performance solution for high frequency RF, microwave, or optical amplification needs. This 50Ω gain block is based on a reliable HBT proprietary MMIC design, providing unsurpassed performance for small-signal applications. Designed with an external bias resistor, the NDA-320-D provides flexibility and stability. In addition, the NDA-320-D chip was designed with an additional ground via, providing improved thermal resistance performance. The NDA-series of distributed amplifiers provide design flexibility by incorporating AGC functionality into their designs.



Package Style: Die

Optimum Technology Matching® Applied

- ☐ Si BJT
- ☐ Si Bi-CMOS
- ☑ GaInP/HBT
- ☐ GaAs HBT
- ☐ SiGe HBT
- ☐ GaN HEMT
- ☐ GaAs MESFET
- ☐ Si CMOS

Features

- Reliable, Low-Cost HBT Design
- 10.0dB Gain at 6GHz
- High P1dB of +13.5dBm @ 2GHz
- Fixed Gain or AGC Operation
- 50Ω I/O Matched for High Freq. Use

Ordering Information

NDA-320-D	GaInP/GaAs HBT MMIC Distributed Amplifier DC to 12GHz - Die Only

RF Micro Devices, Inc.
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Functional Block Diagram

Absolute Maximum Ratings

Parameter	Rating	Unit
RF Input Power	+20	dBm
Power Dissipation	300	mW
Device Current, I_{CC1}	42	mA
Device Current, I_{CC2}	48	mA
Junction Temperature, Tj	200	°C
Operating Temperature	-45 to +85	°C
Storage Temperature	-65 to +150	°C

Exceeding any one or a combination of these limits may cause permanent damage.

Caution! ESD sensitive device.

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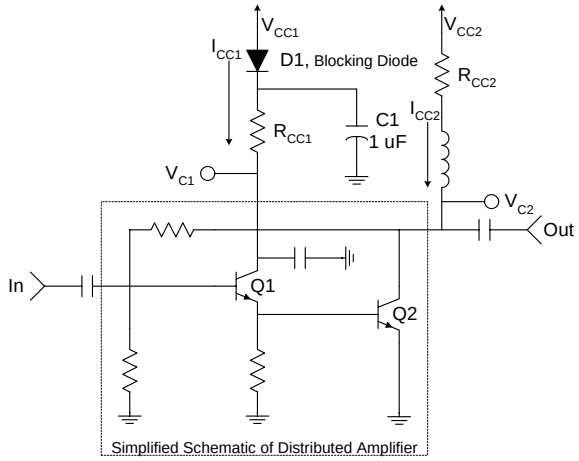
Parameter	Specification			Unit	Condition
	Min.	Typ.	Max.		
Overall					V_{CC1}=+10V, V_{CC2}=+10V, V_{C1}=+4.75V, V_{C2}=+2.98V, I_{CC1}=24mA, I_{CC2}=40mA, Z_0=50Ω, T_A=+25°C
Small Signal Power Gain, S21	8.5	9.5		dB	f=0.1GHz to 4.0GHz
		10.5		dB	f=4.0GHz to 8.0GHz
	6.0	7.0		dB	f=8.0GHz to 12.0GHz
Gain Flatness		±0.6		dB	f=0.1GHz to 8.0GHz
Input and Output VSWR		1.45:1			f=0.1GHz to 8.0GHz
		1.95:1			f=8.0GHz to 12.0GHz
Bandwidth, BW		12.5		GHz	BW3 (3dB)
Output Power @ 1dB Compression		13.5		dBm	f=2.0GHz
		13.5		dBm	f=6.0GHz
		10.0		dBm	f=14.0GHz
Noise Figure, NF		5.5		dB	f=2.0GHz
Third Order Intercept, IP3		23.5		dBm	f=2.0GHz
Reverse Isolation, S12		-14		dB	f=0.1GHz to 12.0GHz
Device Voltage, V_Z	3.6	4.0	4.2	V	
AGC Control Voltage, V_{C1}		4.7		V	
Gain Temperature Coefficient, $\delta G_T/\delta T$		-0.0015		dB/°C	
MTTF versus Junction Temperature					
Case Temperature		85		°C	
Junction Temperature		113.9		°C	
MTTF		>1,000,000		hours	
Thermal Resistance					
θ_{JC}		124		°C/W	Thermal Resistance, at any temperature (in °C/Watt) can be estimated by the following equation: θ_{JC} (°C/Watt)=124[T_J(°C)/113]

Suggested Voltage Supply: V_{CC1}≥4.7V, V_{CC2}≥5.0V

Typical Bias Configuration

Application notes related to biasing circuit, device footprint, and thermal considerations are available on request.



Simplified Schematic of Distributed Amplifier

Bias Resistor Selection
R_{CC1}: For 4.7V<V_{CC1}<5.0V R_{CC1}=0Ω For 5.0V<V_{CC1}<10.0V R_{CC1}=V_{CC1}-4.7/0.024Ω
R_{CC2}: For 5.0V<V_{CC2}<10.0V R_{CC1}=V_{CC2}-2.98/0.040Ω

Typical Bias Parameters for V_{CC1}=V_{CC2}=10V:							
V_{CC1} (V)	V_{CC2} (V)	I_{CC1} (mA)	V_{C1} (V)	R_{CC1} (Ω)	I_{CC2} (mA)	V_{C2} (V)	R_{CC2} (Ω)
10	10	24	4.75	220	40	3.98	150

Application Notes

Die Attach

The die attach process mechanically attaches the die to the circuit substrate. In addition, it electrically connects the ground to the trace on which the chip is mounted, and establishes the thermal path by which heat can leave the chip.

Wire Bonding

Electrical connections to the chip are made through wire bonds. Either wedge or ball bonding methods are acceptable practices for wire bonding.

Assembly Procedure

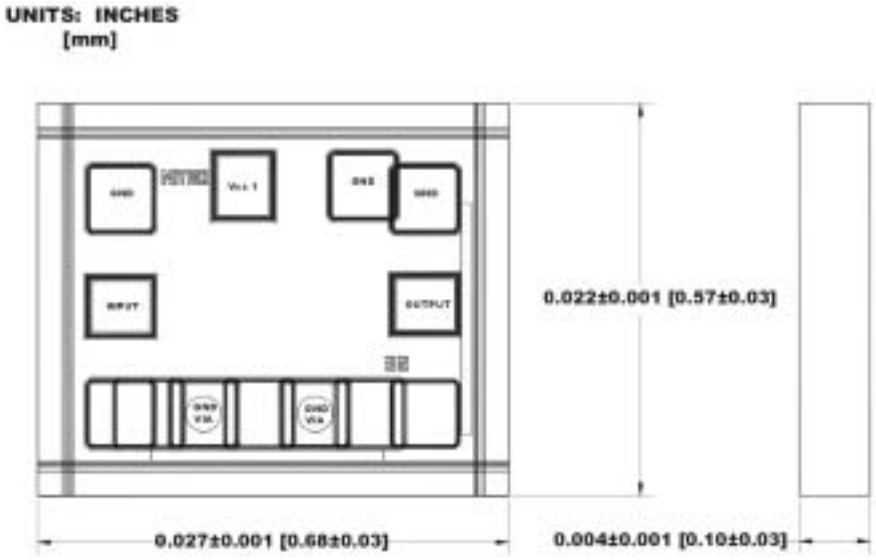
Epoxy or eutectic die attach are both acceptable attachment methods. Top and bottom metallization are gold. Conductive silver-filled epoxies are recommended. This procedure involves the use of epoxy to form a joint between the backside gold of the chip and the metallized area of the substrate. A 150°C cure for 1 hour is necessary. Recommended epoxy is Ablebond 84-1LMI from Ablestik.

Bonding Temperature (Wedge or Ball)

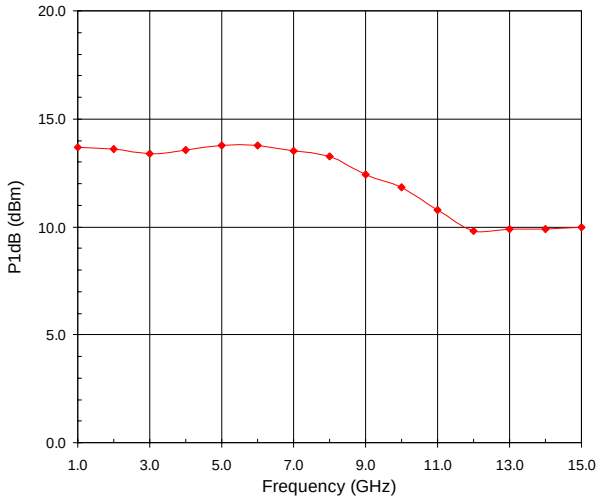
It is recommended that the heater block temperature be set to 160°C±10°C.

Chip Outline Drawing - NDA-320-D

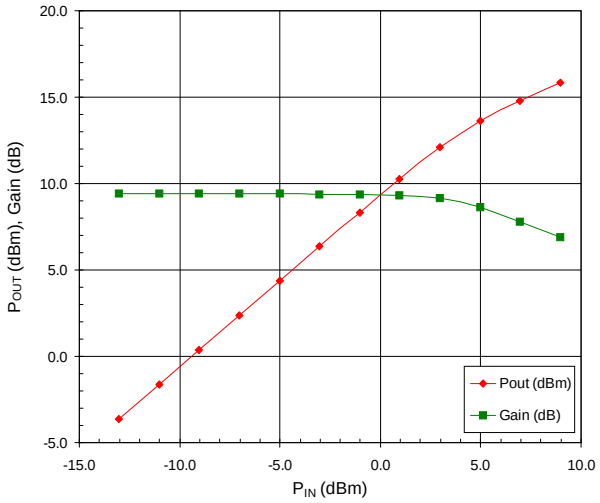
Chip Dimensions: 0.027” x 0.022” x 0.004”



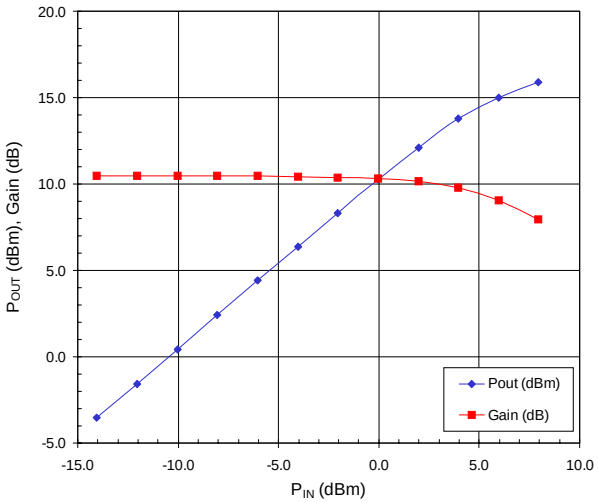
P1dB versus Frequency at 25°C



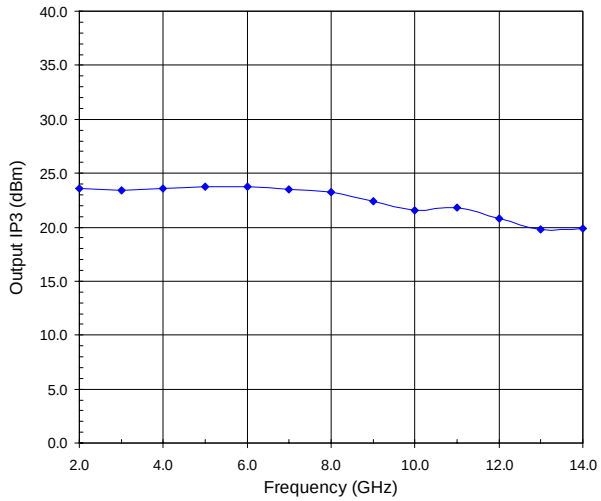
P_{OUT}/Gain versus P_{IN} at 2 GHz



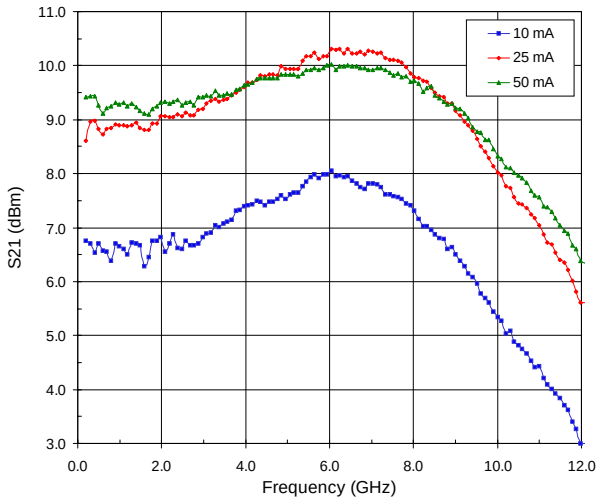
P_{OUT}/Gain versus P_{IN} at 6 GHz



Third Order Intercept versus Frequency at 25°C



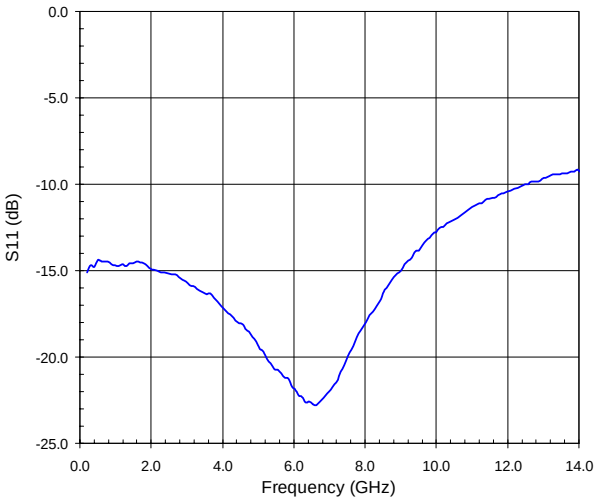
Gain (S21) for AGC Mode Operation



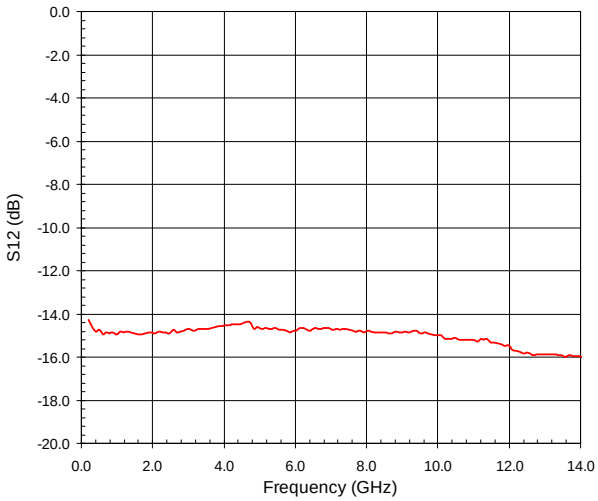
Note: The s-parameter gain results shown below include device performance as well as evaluation board and connector loss variations. The insertion losses of the evaluation board and connectors are as follows:

1GHz to 4GHz=-0.06dB
5GHz to 9GHz=-0.22dB
10GHz to 14GHz=-0.50dB
15GHz to 20GHz=-1.08dB

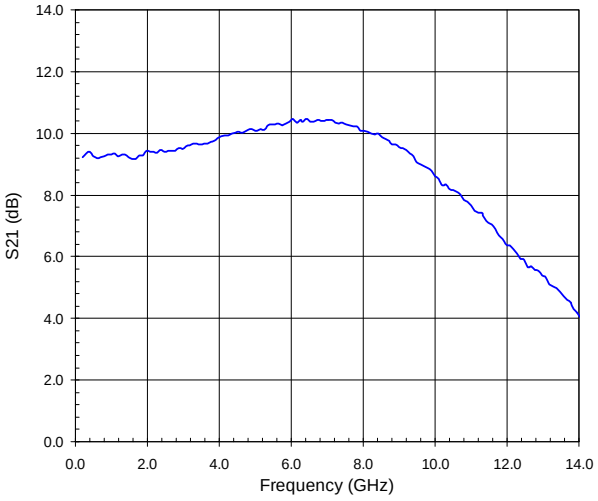
S11 versus Frequency



S12 versus Frequency



S21 versus Frequency



S22 versus Frequency